

*IN THE UNITED STATES PATENT AND TRADEMARK OFFICE*

In re PATENT APPLICATION of :  
Hitoshi ENDO et al. :  
Serial No. [NEW] :  
Filed: September 24, 2003 :  
For: TEST METHOD OF MEMORY IC FUNCTION ON DEVICE BOARD  
WITH DYNAMIC COMPETING CYCLE

**PRELIMINARY AMENDMENT**

U.S. Patent and Trademark Office  
2011 South Clark Place  
**Customer Window, Mail Stop New Application**  
Crystal Plaza Two, Lobby, Room 1B03  
Arlington, VA 22202

Sir:

Preliminary to the examination of the above-identified application, please  
enter the following amendments and consider the following remarks:

**Amendments to the Specification** begin on page 2 of this paper.

**Remarks/Arguments** begin on page 3 of this paper.